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Structure and domain formation in ferroelectric thin films

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Document Version

Publisher's PDF, also known as Version of record

Publication date:

2009

[Link to publication in University of Groningen/UMCG research database](#)

Citation for published version (APA):

Vlooswijk, A. H. G. (2009). *Structure and domain formation in ferroelectric thin films*. [Thesis fully internal (DIV), University of Groningen]. [s.n.].

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Contents

Abstract	v
Samenvatting	ix
Motivation and outline	1
1 General introduction	5
1.1 Introduction	5
1.2 Thin films	6
1.2.1 Stress and (misfit) strain	6
1.2.2 Lattice relations	7
1.3 Ferroelectricity and related concepts	9
1.3.1 Crystals and symmetry in ferroelectrics	9
1.3.2 The mechanism of ferroelectricity	11
1.3.3 Phase transitions	15
1.3.4 Ferroelectric and ferroelastic domains	16
1.3.5 Materials for applications	18
2 State of the art of ferroelectrics	21
2.1 Introduction	21
2.2 Classical ferroelectrics and solid solutions	22
2.3 Chemical pressure and epitaxial strain	24
2.4 Bulk ferroelectric perovskites	28
2.4.1 First principles	28
2.4.2 Phenomenology	30

2.5	Thin films of ferroelectric perovskites	33
2.5.1	Ultrathin films	34
2.5.2	Phenomenology of thin films	34
2.5.3	Tetragonality	39
2.6	Domain structures in ferroelectric perovskites	41
2.6.1	180° domains	41
2.6.2	Critical thickness for strain relaxation	46
2.6.3	90° domains	48
3	Thin film technology & analysis	51
3.1	Introduction	51
3.2	Monitored thin film growth	52
3.2.1	Pulsed Laser Deposition (PLD)	52
3.2.2	Supersaturation & growth modes	54
3.2.3	Reflection High Energy Electron Diffraction (RHEED)	57
3.3	Substrates	60
3.4	Targets and stoichiometry	64
3.5	Structural and morphological characterization	66
3.5.1	Structural characterization	67
3.5.2	Morphological characterization	74
3.6	Electrical characterization	75
3.6.1	Impedance spectroscopy	76
3.6.2	CV-characteristics	77
4	“Small” compressive strain	81
4.1	Introduction	81
4.2	Thin film growth	83
4.3	Thin film characterization	85
4.3.1	Double diffraction	85
4.3.2	Compositional properties	91
4.4	Results and discussion	92
4.4.1	90° domain formation: critical thickness and growth rate	92
4.4.2	180° domain formation	97
4.4.3	Electrical properties	102
4.5	Conclusions	105

5	“Large” anisotropic strain	109
5.1	Introduction	109
5.2	Experimental considerations	111
5.2.1	Substrate treatment	111
5.2.2	The DyScO ₃ surface	113
5.3	Results and discussion	116
5.3.1	90° domains	116
5.3.2	Critical thickness for strain relaxation	123
5.3.3	Strain gradients	128
5.3.4	180° domains	132
5.3.5	Electrical boundary conditions	136
5.4	Conclusions	140
6	Ferroelectric nanostructures	143
6.1	Introduction	143
6.2	Chains of PbTiO ₃ nanodots	144
6.2.1	Introduction	144
6.2.2	Experimental	145
6.2.3	Results and discussion	148
6.3	PbTiO ₃ / SrTiO ₃ superlattices	151
6.3.1	Introduction	151
6.3.2	Experimental	151
6.3.3	Results and discussion	152
6.4	Conclusions	158
	List of Publications	161
	Dankwoord	162
	Appendix	166
	Bibliography	169

